

Notice of References Cited	Application/Control No. 09/728,292	Applicant(s)/Patent Under Reexamination YEN ET AL.	
	Examiner Nadia Khoshnoodi	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,601,172	07-2003	Epstein, Michael	713/178
	B	US-5,153,928	10-1992	Iizuka, Nobuo	382/321
	C	US-5,490,217	02-1996	Wang et al.	380/51
	D	US-6,611,598	08-2003	Hayosh, Thomas David	380/54
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08185451 A	07-1996	Japan	KATO, TAKAHIRO	G06F 19/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sabourin et al., Off-line Signature Verification by Local Granulometric Size Distributions, September 1997, Vol. 19 Issue 9, pages 976-982
	V	Sabourin et al., Pattern Spectrum as a Local Shape Factor for Off-line Signature Verification, August 1996, Vol. 3, pages 43-48
	W	Sabourin et al., An Extended-Shadow-Code Based Approach for Off-line Signature Verification. I. Evaluation of the Bar Mask Definition, October 1994, Vol. 2, pages 450-453
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.